



GENERAL DESCRIPTION

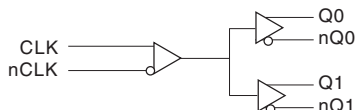


The ICS85411 is a low skew, high performance 1-to-2 Differential-to-LVDS Fanout Buffer and a member of the HiPerClockSTM family of High Performance Clock Solutions from ICS. The CLK, nCLK pair can accept most standard differential input levels. The ICS85411 is characterized to operate from a 3.3V power supply. Guaranteed output and part-to-part skew characteristics make the ICS85411 ideal for those clock distribution applications demanding well defined performance and repeatability.

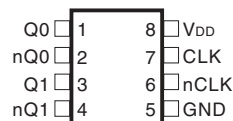
FEATURES

- 2 differential LVDS outputs
- 1 differential CLK, nCLK clock input
- CLK, nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- Maximum output frequency: 650MHz
- Translates any single ended input signal to LVDS levels with resistor bias on nCLK input
- Output skew: 20ps (maximum)
- Part-to-part skew: 250ps (maximum)
- Additive phase jitter, RMS: 0.05ps (typical)
- Propagation delay: 2.5 ns (maximum)
- 3.3V operating supply
- 0°C to 70°C ambient operating temperature
- Lead-Free package available
- Industrial temperature information available upon request

BLOCK DIAGRAM



PIN ASSIGNMENT



ICS85411
8-Lead SOIC

3.90mm x 4.90mm x 1.37mm package body

M Package
Top View



TABLE 1. PIN DESCRIPTIONS

Number	Name	Type		Description
1, 2	Q0, nQ0	Output		Differential output pair. LVDS interface levels.
3, 4	Q1, nQ1	Output		Differential output pair. LVDS interface levels.
5	GND	Power		Power supply ground.
6	nCLK	Input	Pulldown	Inverting differential clock input.
7	CLK	Input	Pullup	Non-inverting differential clock input.
8	V _{DD}	Power		Positive supply pin.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

TABLE 2. PIN CHARACTERISTICS

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		KΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		KΩ



ABSOLUTE MAXIMUM RATINGS

Supply Voltage, V_{DD}	4.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, I_O	
Continuous Current	10mA
Surge Current	15mA
Package Thermal Impedance, θ_{JA}	112.7°C/W (0 lfpm)
Storage Temperature, T_{STG}	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

TABLE 3A. POWER SUPPLY DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
I_{DD}	Power Supply Current				50	mA

TABLE 3B. DIFFERENTIAL DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
I_{IH}	Input High Current	CLK $V_{DD} = V_{IN} = 3.465V$			5	μA
		nCLK $V_{DD} = V_{IN} = 3.465V$			150	μA
I_{IL}	Input Low Current	CLK $V_{DD} = 3.465V, V_{IN} = 0V$	-150			μA
		nCLK $V_{DD} = 3.465V, V_{IN} = 0V$	-5			μA
V_{PP}	Peak-to-Peak Input Voltage		0.15		1.3	V
V_{CMR}	Common Mode Input Voltage; NOTE 1, 2		0.5		$V_{DD} - 0.85$	V

NOTE 1: Common mode voltage is defined as V_{IH} .

NOTE 2: For single ended applications, the maximum input voltage for CLK, nCLK is $V_{DD} + 0.3V$.

TABLE 3C. LVDS DC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		200	280	360	mV
ΔV_{OD}	VOD Magnitude Change			0	40	mV
V_{OS}	Offset Voltage		1.125	1.25	1.375	V
ΔV_{OS}	VOS Magnitude Change			5	25	mV
I_{OFF}	Power Off Leakage		-20	± 1	+20	μA
I_{OSD}	Differential Output Short Circuit Current			-3.5	-5	mA
I_{OS}	Output Short Circuit Current			-3.5	-5	mA
V_{OH}	Output High Voltage			1.34	1.6	V
V_{OL}	Output Low Voltage		0.9	1.06		V



TABLE 4. AC CHARACTERISTICS, $V_{DD} = 3.3V \pm 5\%$ $T_A = 0^\circ C$ TO $70^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{MAX}	Output Frequency				650	MHz
t_{PD}	Propagation Delay; NOTE 1		1.5		2.5	ns
$t_{sk(o)}$	Output Skew; NOTE 2, 4				20	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 3, 4				250	ps
f_{jit}	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	(12KHz to 20MHz)		0.05		ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	150		350	ps
odc	Output Duty Cycle	> 500MHz	47		53	%
		$\leq 500MHz$	48		52	%

All parameters measured at $f \leq 650MHz$ unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the output differential cross points.

NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

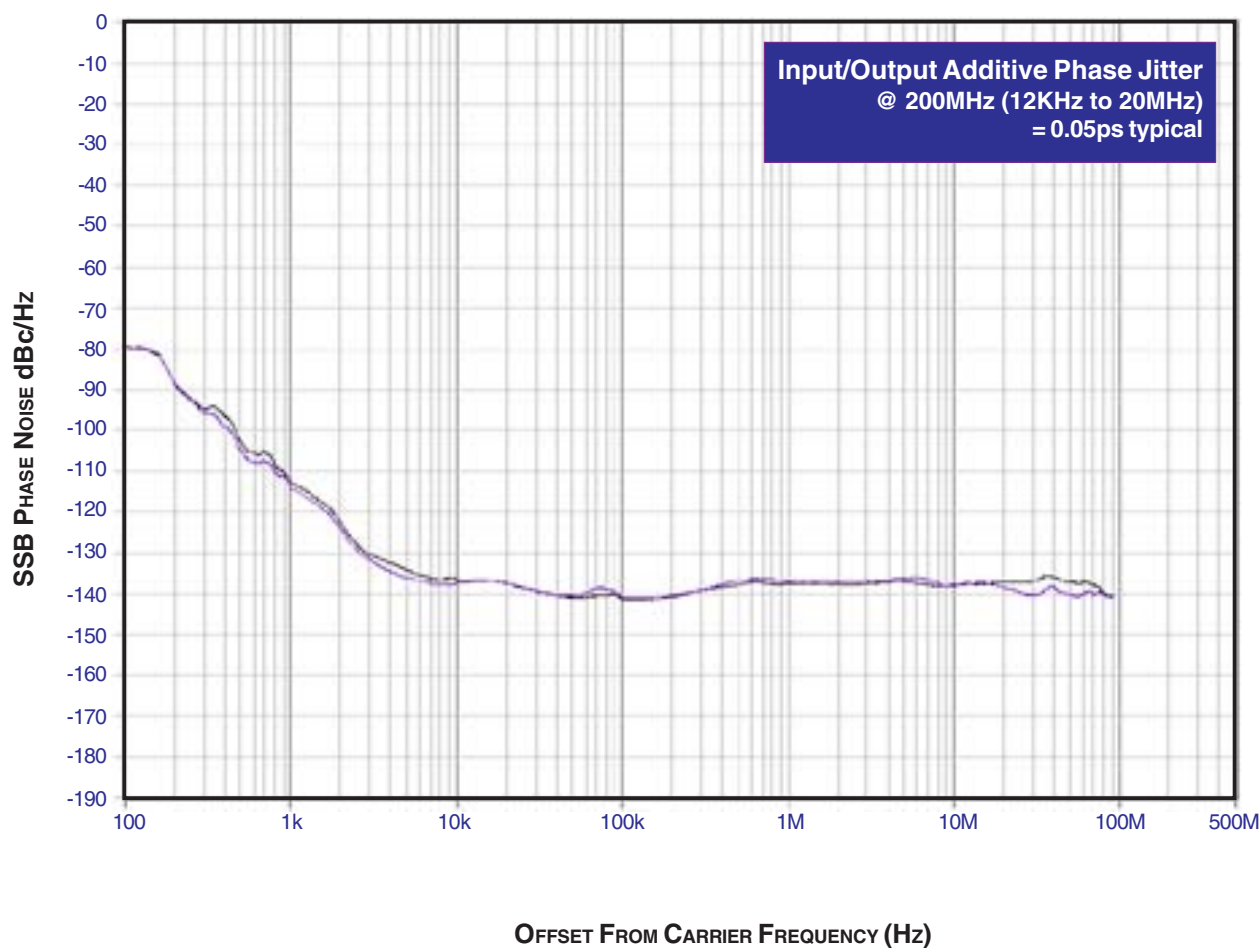
NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.



ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the **dBc Phase Noise**. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in

the 1Hz band to the power in the fundamental. When the required offset is specified, the phase noise is called a **dBc** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

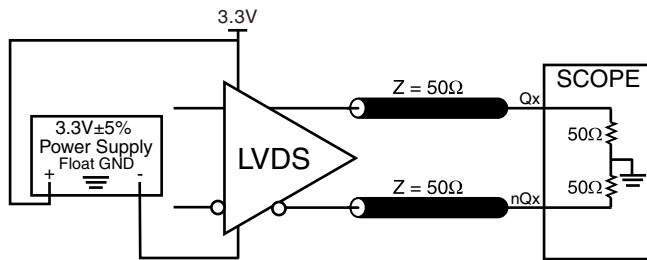


As with most timing specifications, phase noise measurements have issues. The primary issue relates to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device. This is illustrated above. The de-

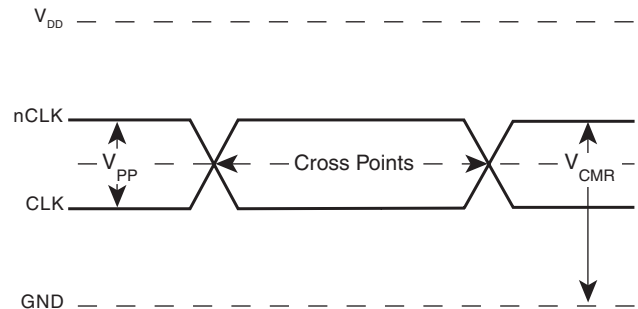
vice meets the noise floor of what is shown, but can actually be lower. The phase noise is dependant on the input source and measurement equipment.



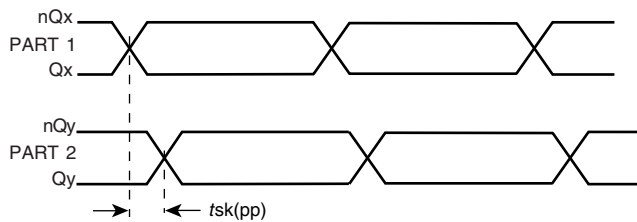
PARAMETER MEASUREMENT INFORMATION



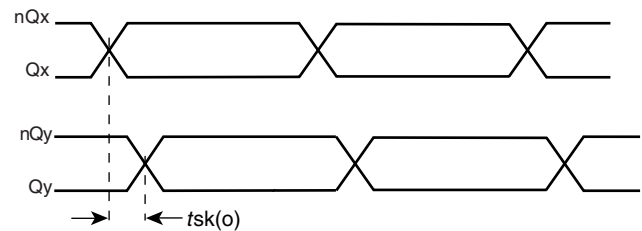
3.3V OUTPUT LOAD AC TEST CIRCUIT



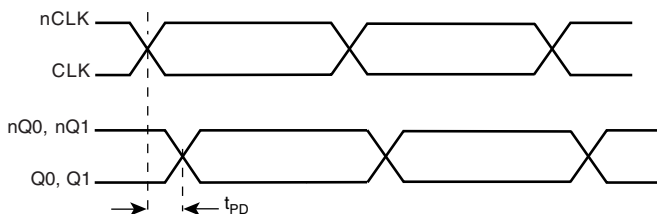
DIFFERENTIAL INPUT LEVEL



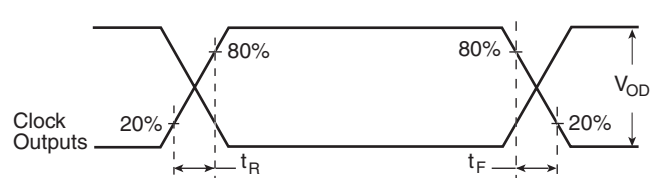
PART-TO-PART SKEW



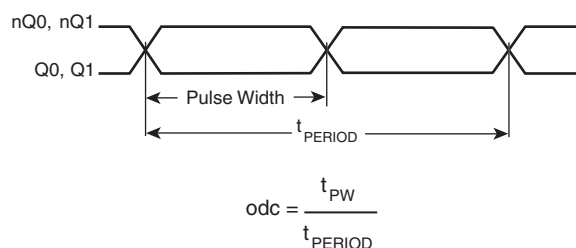
OUTPUT SKEW



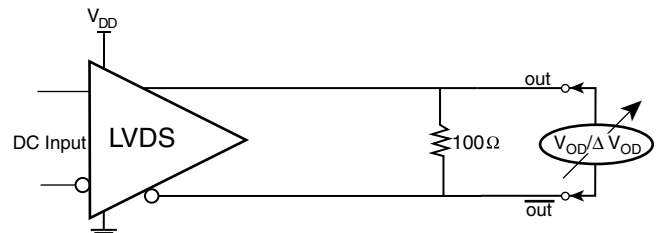
PROPAGATION DELAY



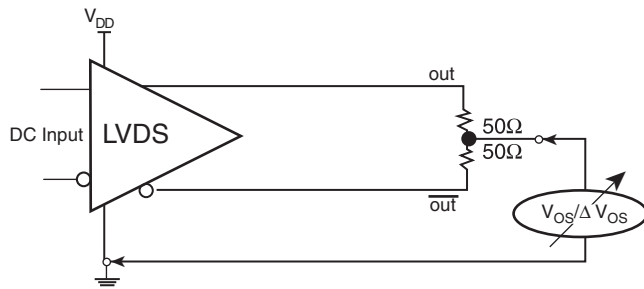
OUTPUT RISE/FALL TIME



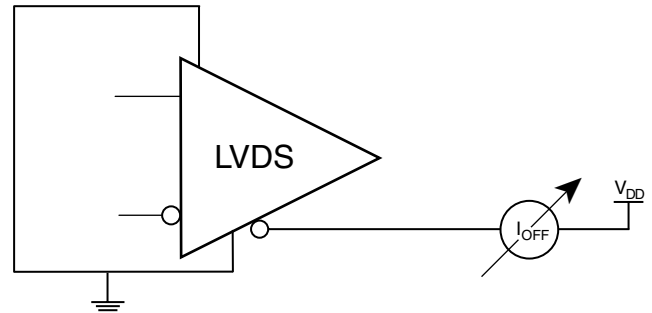
OUTPUT DUTY CYCLE/PULSE WIDTH/PERIOD



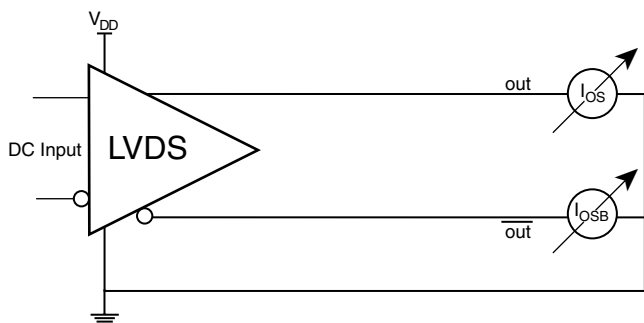
DIFFERENTIAL OUTPUT VOLTAGE SETUP



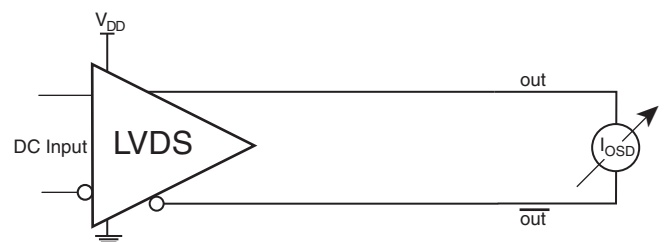
OFFSET VOLTAGE SETUP



POWER OFF LEAKAGE SETUP



OUTPUT SHORT CIRCUIT CURRENT SETUP



DIFFERENTIAL OUTPUT SHORT CIRCUIT CURRENT SETUP



APPLICATION INFORMATION

WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage $V_{REF} = V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio

of R1 and R2 might need to be adjusted to position the V_{REF} in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_{REF} should be 1.25V and $R2/R1 = 0.609$.

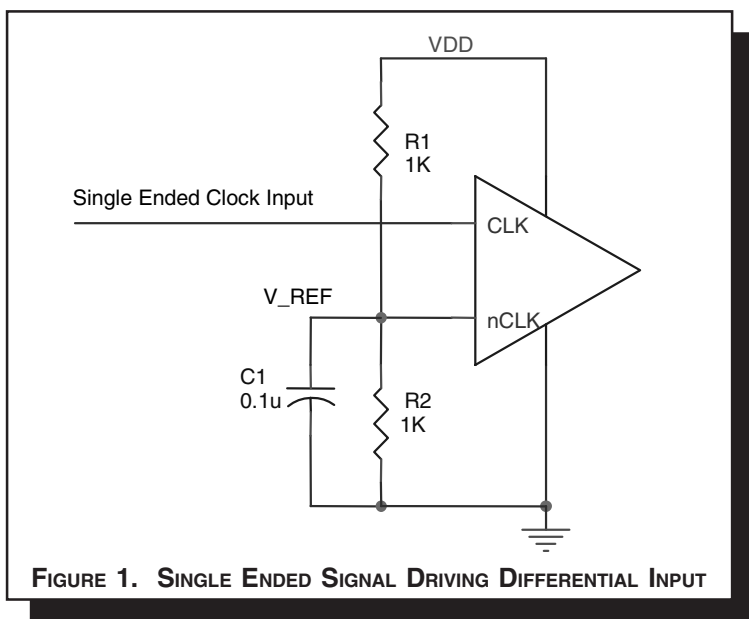


FIGURE 1. SINGLE ENDED SIGNAL DRIVING DIFFERENTIAL INPUT

LVDS DRIVER TERMINATION

A general LVDS interface is shown in Figure 2. In a 100Ω differential transmission line environment, LVDS drivers require a matched load termination of 100Ω across near the

receiver input. For a multiple LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the un-used outputs.

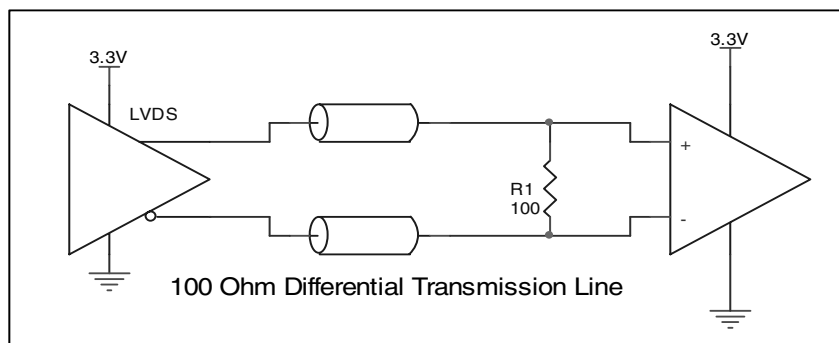


FIGURE 2. TYPICAL LVDS DRIVER TERMINATION



DIFFERENTIAL CLOCK INPUT INTERFACE

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both V_{SWING} and V_{OH} must meet the V_{PP} and V_{CMR} input requirements. Figures 3A to 3E show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested

here are examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example in Figure 3A, the input termination applies for ICS HiPerClockS LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

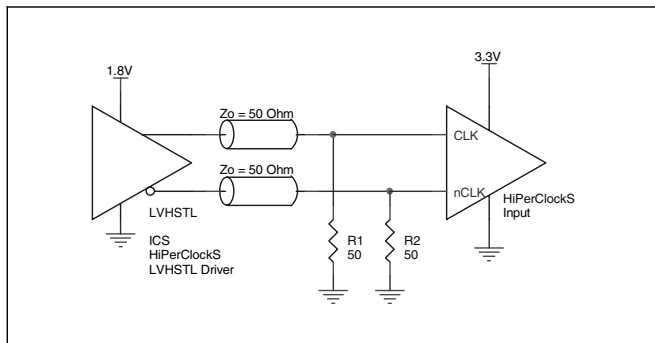


FIGURE 3A. HiPerClockS CLK/nCLK INPUT DRIVEN BY ICS HiPerClockS LVHSTL DRIVER

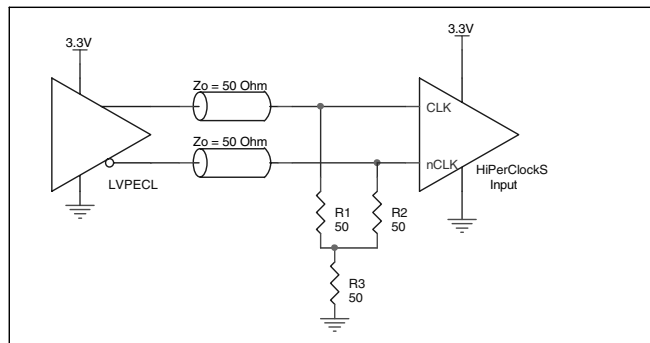


FIGURE 3B. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

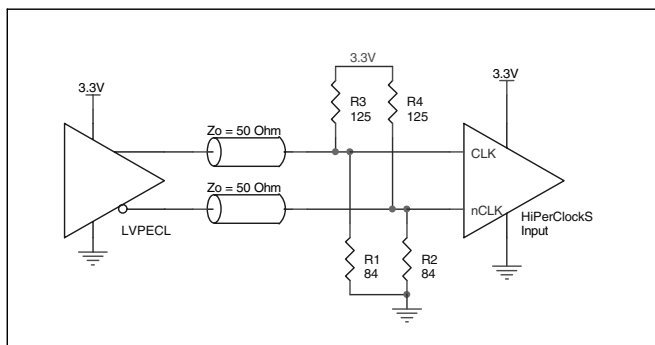


FIGURE 3C. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER

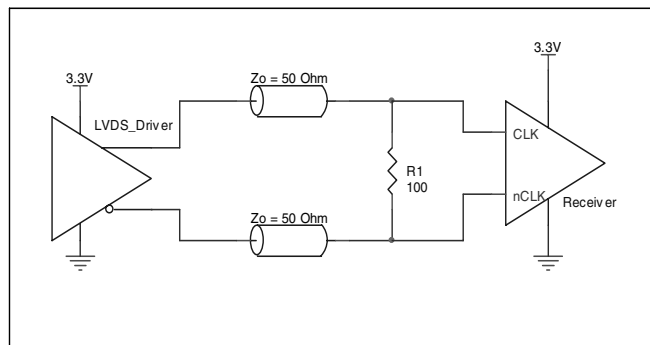


FIGURE 3D. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVDS DRIVER

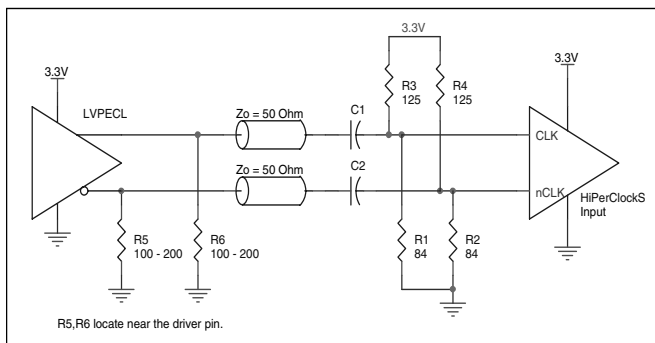


FIGURE 3E. HiPerClockS CLK/nCLK INPUT DRIVEN BY 3.3V LVPECL DRIVER WITH AC COUPLE



RELIABILITY INFORMATION

TABLE 5. θ_{JA} VS. AIR FLOW TABLE FOR 8 LEAD SOIC

θ_{JA} by Velocity (Linear Feet per Minute)			
	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	153.3°C/W	128.5°C/W	115.5°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	112.7°C/W	103.3°C/W	97.1°C/W

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

TRANSISTOR COUNT

The transistor count for ICS85411 is: 636



PACKAGE OUTLINE - M SUFFIX FOR 8 LEAD SOIC

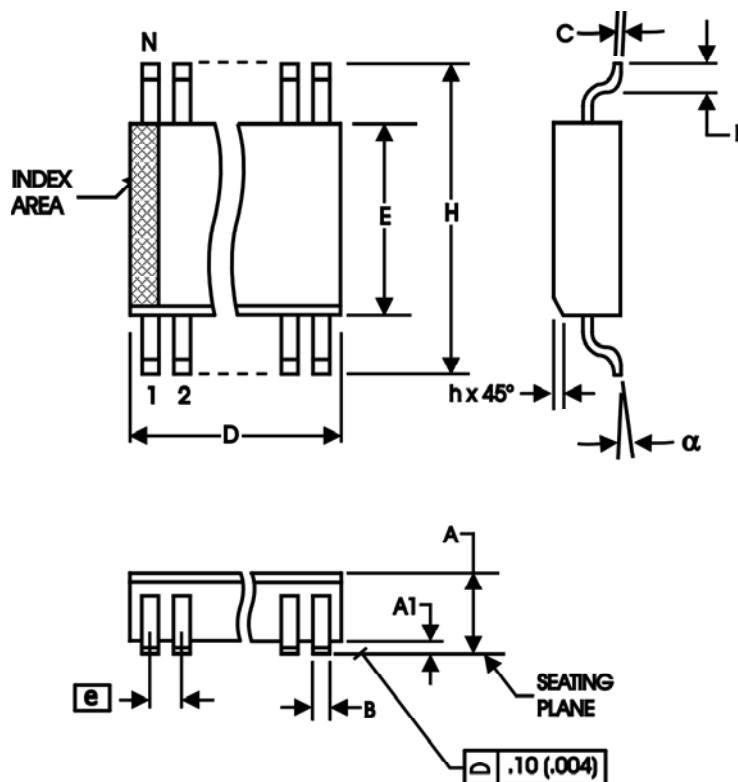


TABLE 6. PACKAGE DIMENSIONS

SYMBOL	Millimeters	
	MINIMUM	MAXIMUM
N	8	
A	1.35	1.75
A1	0.10	0.25
B	0.33	0.51
C	0.19	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BASIC	
H	5.80	6.20
h	0.25	0.50
L	0.40	1.27
α	0°	8°

Reference Document: JEDEC Publication 95, MS-012



Integrated
Circuit
Systems, Inc.

ICS85411

LOW SKEW, 1-TO-2 DIFFERENTIAL-TO-LVDS FANOUT BUFFER

TABLE 7. ORDERING INFORMATION

Part/Order Number	Marking	Package	Count	Temperature
ICS85411AM	85411AM	8 lead SOIC	96 per tube	0°C to 70°C
ICS85411AMT	85411AM	8 lead SOIC on Tape and Reel	2500	0°C to 70°C
ICS85411AMLF	85411AMLF	8 lead "Lead Free" SOIC	96 per tube	0°C to 70°C
ICS85411AMLFT	85411AMLF	8 lead "Lead Free" SOIC on Tape and Reel	2500	0°C to 70°C

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ICS85411

LOW SKEW, 1-TO-2 DIFFERENTIAL-TO-LVDS FANOUT BUFFER

REVISION HISTORY SHEET				
Rev	Table	Page	Description of Change	Date
B	T4	1	Features - added Additive Phase Jitter bullet.	6/9/04
		4	AC Characteristics table - added tjit row.	
		5	Added Additive Phase Jitter Application Note	
B	T7	12	Ordering Information Table - added Lead Free Part Number.	6/16/04